

ABSTRACT OF THE DISCLOSURE:

**TITLE: SYSTEM FOR TESTING MULTIPLE GROUPS OF IC-CHIPS
 WHICH CONCURRENTLY SENDS TIME-SHIFTED TEST
 SIGNALS TO THE GROUPS**

 An electromechanical system for testing IC-chips includes a total of N chip holding subassemblies; a moving mechanism for automatically moving the i -th chip holding subassembly from a load position in the system to
5 the test position in the system, and visa-versa, where i ranges from 1 to N and changes with time in a sequence; and a signal generator which sends test signals to the IC-chips at the test position. Between the moving of the i -th chip holding subassembly and the next subassembly in
10 the sequence, test signals are sent to the IC-chips on all N of the chip holding subassemblies such that the signals are shifted in time from one subassembly to another. Also, while the i -th chip holding subassembly is being moved, the time shifted test signals continue to
15 be sent to the IC-chips on the remaining $N-1$ chip holding subassemblies.